Hybrid 7z26 Traveler

March 20, 2000

1 Connectivity

Repairs on short.
Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 7Z26 has die: 119-034 119-037 119-040 119-041 119-042 119-043 119-045

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

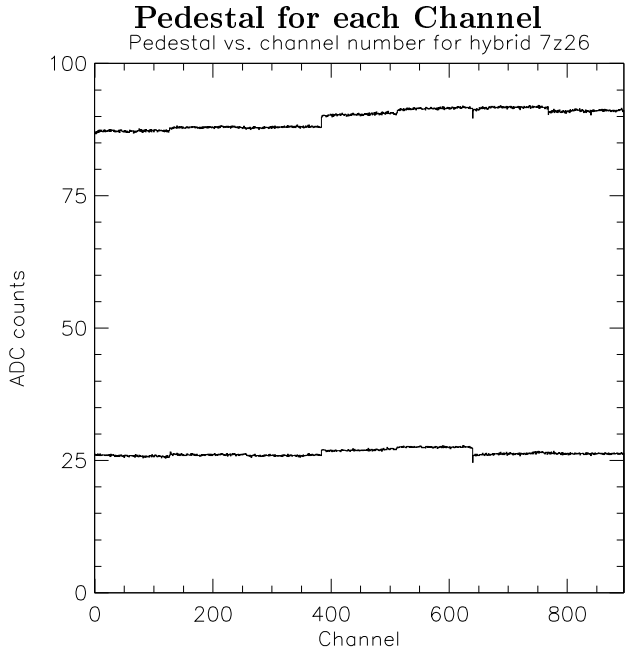
```
% Hybrid 7z26 classification info. Created 13:04:21 02/06/00

Hybrid 7z26 quality: fair
Chip classification: good good fair good good fair good
Bad channels (chip-channel): 2-62
Bad cells: none
Random bad capacitors (chip-cell-channel): 5-19-0
Channels at pedestal needed for DCMS: 40.2 33.7 40.7 35.7 32.7 33.7 38.3
```

4 Comments

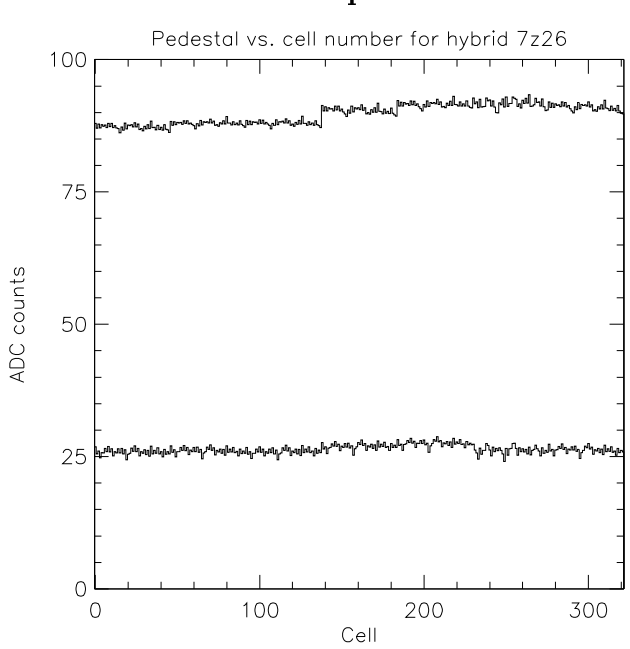
Encapsulated. Has Au DVDD and DGND wirebonds. HV tested.

5 Pedestal

The following plot shows the pedestals vs. channel number with and without charge injection:



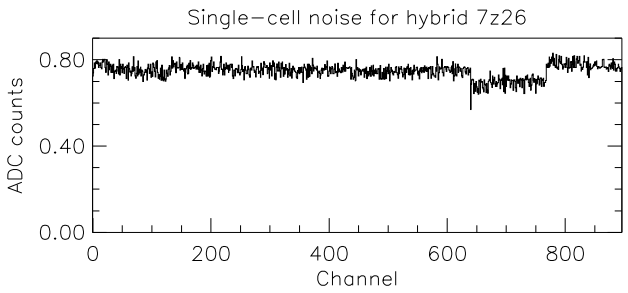
The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

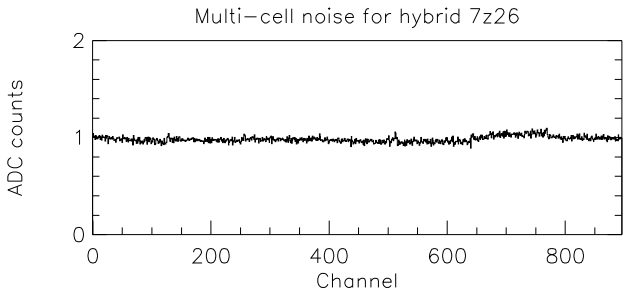


6 Noise

The following plots show the single-cell and multi-cell RMS noise:

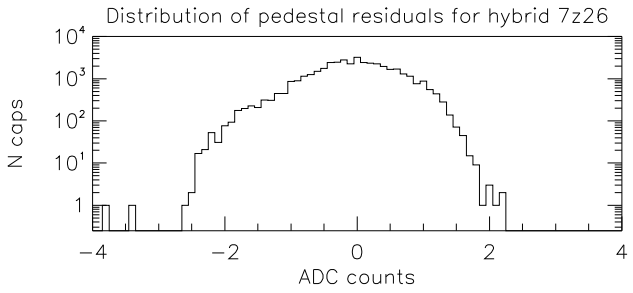
RMS Noise

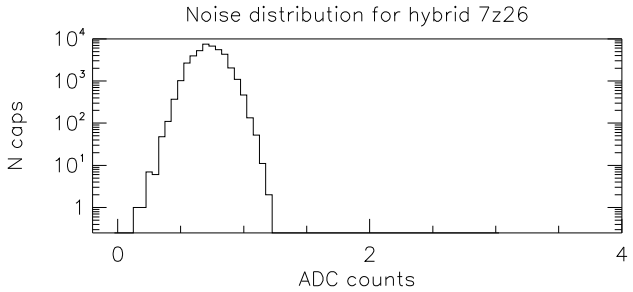




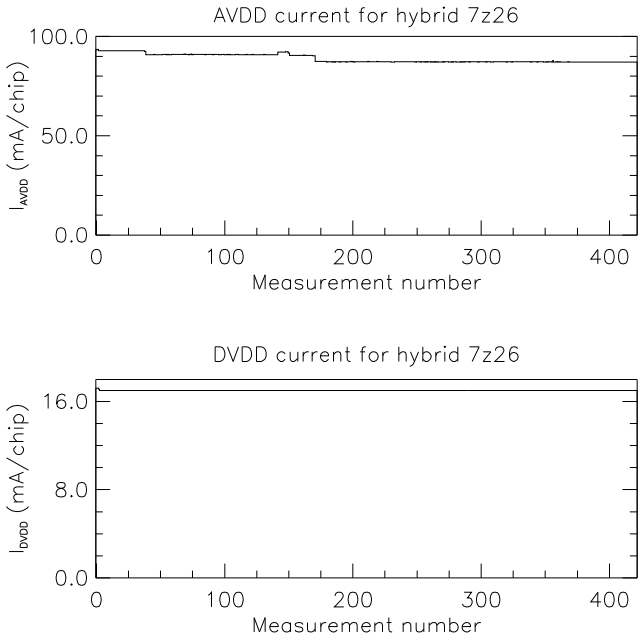
The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise





7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in